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|-----------------------------------|--|----------------------------|--------------------------------------------------------|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination GANS ET AL. | |
| | | Examiner Viet Q. Nguyen | Art Unit 2827 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|--------------------------------------------------|-----------------|-------------------|----------------|
| A | US-5,301,155 | 04-1994 | Wada et al. | 365/201 |
| B | US-5,523,980 | 06-1996 | Sakui et al. | 365/230.08 |
| C | US-6,072,719 | 06-2000 | Tanzawa et al. | 365/185.03 |
| D | US-6,856,544 | 02-2005 | Nakamura, Hiroshi | 365/185.11 |
| E | US-5,498,990 | 03-1996 | Leung et al. | 327/323 |
| F | US-5,293,212 | 03-1994 | Yamamoto et al. | 365/218 |
| G | US-4,942,556 | 07-1990 | Sasaki et al. | 365/200 |
| H | US-6,621,755 | 09-2003 | Gans et al. | 365/230.03 |
| I | US-6,249,479 | 06-2001 | Tanzawa et al. | 365/230.06 |
| J | US-6,846,544 | 01-2005 | Buchman, James E. | 428/83 |
| K | US-6,347,063 | 02-2002 | Dosaka et al. | 365/233 |
| L | US-6,661,719 | 12-2003 | Shih et al. | 365/201 |
| M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|--------------------------------------------------|-----------------|---------|------|----------------|
| N | | | | | |
| O | | | | | |
| P | | | | | |
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| R | | | | | |
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NON-PATENT DOCUMENTS

| | | | |
|---|-------------------------------------------------------------------------------------------|--|--|
| * | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | | |
| U | | | |
| V | | | |
| W | | | |
| X | | | |

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